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		[Fig.	1]
		s0	sets the entered slice level to a predetermined one $\circ f$
		S1	measures jitter to produce a measured jitter
			value A
	5	S2	increments the slice level in steps of Si
		s3	measures the jitter and produces a measured
			jitter value B
		S5	stops the incrementing of the slice level, and measures
		jitte	r quantity and produces a measured jitter value C
	10	S6	decrements the slice level in steps of another fixed
		quant	ity Sd (< Si)
		s7	measures the jitter and produces a measured jitter value
find than that		D	

SE

```
[Fig. 2]
```

- A jitter ·
- B reference slice level
- C slice level

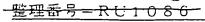
5

[Fig. 4]

- A RF signal
- B binarized signal
- 10 4 RF amplifier
 - 5 Decoder
 - 6 Microcomputer

15 [Fig. 5]

- A RF signal
- B binarized signal



【書類名】 図面一 [|| 1]

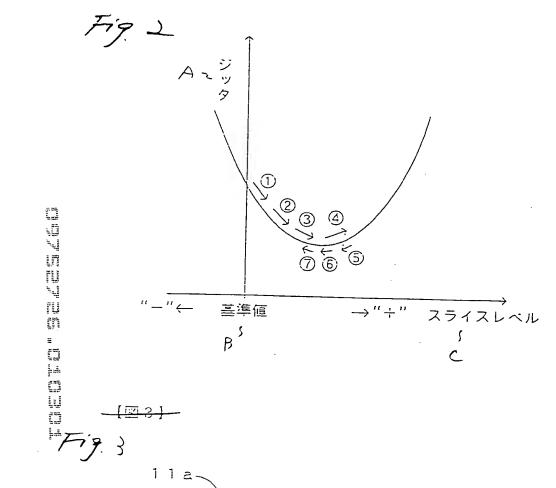
Fig. 1

The first form then the first to make the first first

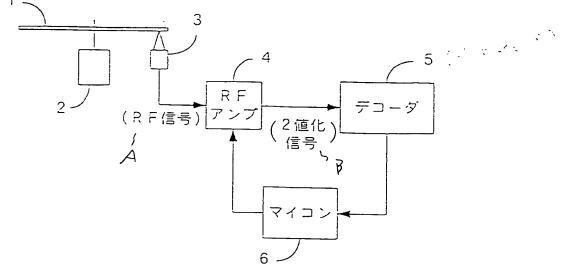
START S 0 スライスレベルを基準 レベルSkに設定 S 1 -ジッタ測定値 A S 2-スライスレベルを Siずつ増加 S 3 -ジッタ測定値 B S 4-ΝΟ A < BYES S 5 -ジッタ測定値C S 6 -スライスレベルを Sd (<Si) ずつ減少 S 7 _ ジッタ測定値 D S 8 - $\widehat{C} < \widehat{D}$ ΝО YES

END

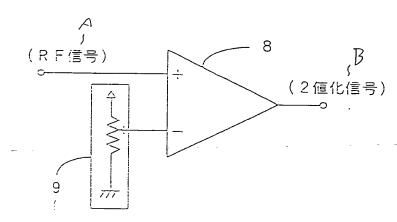


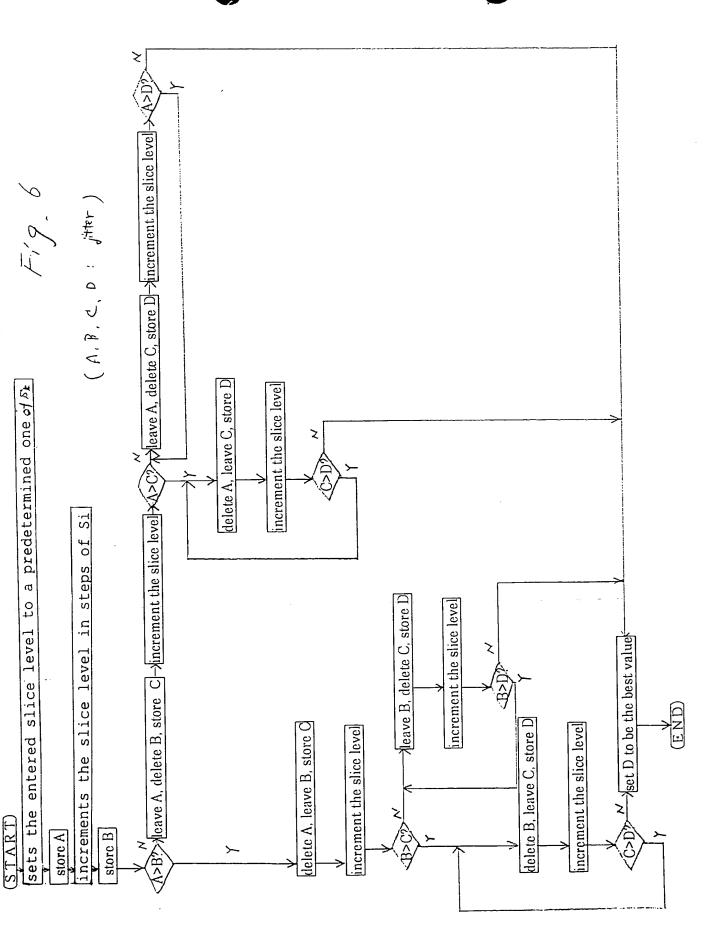


11a-1.3 1 5 11 116



1231 Fig 5





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